

PATENT
Docket No.: 1743/223

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS : Satoru YAMAGUCHI, et al.
SERIAL NO. : (Con. of 09/792,721)
FILED : (Herewith)
FOR : SCANNING ELECTRON MICROSCOPE
GROUP ART UNIT : 2881 (Anticipated)
EXAMINER : Jack I. Berman (Anticipated)

COMMISSIONER FOR PATENTS
P. O. Box 1450
Alexandria, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. § 1.97 & § 1.98

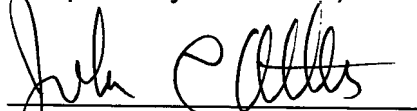
S I R:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

Since all of the references have already been considered in parent application Serial No. 09/792,721, no copies of the references are required.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,



John C. Altmiller
(Reg. No. 25,951)

Date: 10 July 2003

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FORM PTO-1449**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)**

Atty Docket No. : 1743/223
 Serial No. :
 Applicants : S. YAMAGUCHI,, et al.
 Filed :
 Group Art Unit : 2881 (Anticipated)
 Examiner : Jack I. Berman (Anticipated)

U.S. PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Patent Date</u>	<u>Name</u>	<u>Class/ Subclass</u>	<u>Filing Date</u>
	5,087,537	02-1992	CONWAY et al.	250/491.1	
	2002/0185598	12-2002	BOWLEY et al.	250/310	

FOREIGN PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Country</u>	<u>Class/ Subclass</u>	<u>Translation Yes No</u>
	9-245709	09/19/97	Japan		X
	2000-236007	08/29/00	Japan		X
	2000-123771	04/28/00	Japan		X

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner
Initial _____

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.